

#### WIDE AREA FFP MEASUREMENT SYSTEM

FFP measurement and analysis system in combination with dedicated wide area FFP measurement optics & image processing method.

Wide area FFP measurement system is a radiation angle distribution (far field pattern) measurement system that uses wide area FFP measurement optics M-Scope type FW with the measurement target luminous flux diameter of about 3 mm. It is suitable for FFP measurement, emission angle distribution measurement, N.A. measurement and analysis of beam emitted from a large area light emitting elements or large core optical fibers.

#### (Features)

- OM-Scope type FW, wide area FFP measurement optics
  - Quick measurement by dedicated wide area f-θ lens optics and image processing method.
  - Covers samples with a wide emission area with a luminous flux diameter of about 3 mmq.
  - Long working distance design with the working distance of approx. 4mm±0.4mm.
- OPossible to measure in 400nm to 1700nm wavelength range by selecting detector.
- Optical beam analysis module AP013, specially designed high-functional image processing software for optical beam profile analysis
  - All-in-one package of PC, optical beam analysis software, detector driver, correction data.
  - High-performance image processing software for optical beam profile measurement Optimetrics BA Standard is pre-installed.

### (Standard component)

OWide area FFP measurement optics selection • 650~1700nm: M-Scope type FW • 400~650nm: M-Scope type FW/BL

OAvailable detector selection

1" CMOS detector ISA061 • 400~1100nm:

• 950~1700nm: VGA InGaAs NIR detector ISA041VH

Optical beam analysis module AP013

• PC for image processing, optical beam analysis software Optometrics BA Standard, detector driver, calibration data, USB kev

OAccessories

• Cables, instruction manuals, etc.

#### [Option]

ODedicated φ35mm ND filter

• NIR (700~1100nm): **NDF NIR35-5** (5 types per set) ● IR (1310~1550nm): NDF IR35-5 (5 types per set)

- Ontics bench
  - Optics bench for fiber measurement with manual stages
  - Vertical setting optics bench

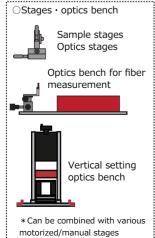
## [Available detectors, angle coverage, pixel resolution (approx.)]

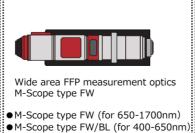
Detector	1" CMOS detector		VGA InGaAs NIR detector	
	ISA061		ISA041VH	
Spectral range	400~1100nm		950~1700nm	
Total pixels	2048×2048 pixels		640×512 pixels	
Pixels pitch	5.5µm sq.		20μm sq.	
Meas. angle /	Meas. angle	Resolution	Meas. angle	Resolution
Pixel resolution	approx. ±43°	approx. 0.05°	approx. ±43°	approx. 0.167°
	N.A. 0.68		(H)×±40°(V)	

<sup>\*</sup>Pixel resolution: Measured angle equivalent to the detector pixel calculated from measured angle range and sensor pitch of the detector.

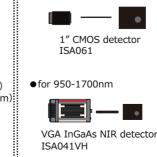
# [Component selection of wide area FFP measurement system]

selection





○Wide area FFP measurement optics



ODetector selection

●for 400~1100nm

